Hacking a 100-ohm Differential Pair

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Agenda

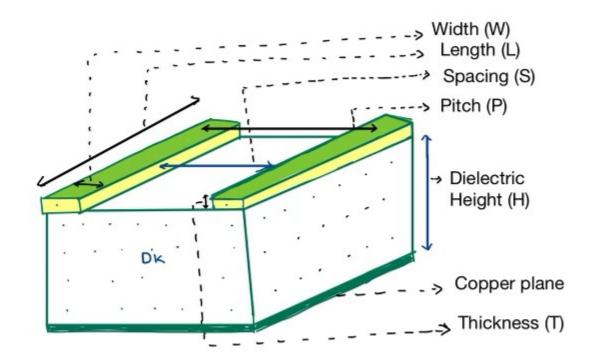
- Transmission Line Parameters
- Differential Pair Setup (DUT)
- Parameters
- Measured Data
- Hacking the circuit
- Observations
- Key Takeaways

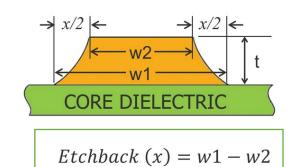


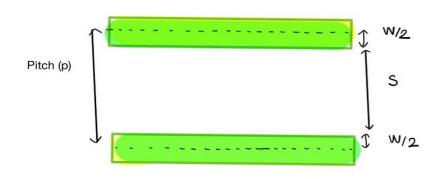




Background







$$Pitch = S + 2*(W/2)$$



DUT – 100-ohm Differential pair







Consistency Check

Known Parameters:

Solder Mask: 0.0254 mm (1 mil)

Copper Thickness: 0.03048 mm (1.2 mils) (Measured w and w/o trace)

Dielectric Height (H) = 1.615mm - 2(0.03556mm) - 2(0.0254mm) =

1.491mm (58.7 mils)







What is the expected data?







Parameters

Parameters	Sec I (Uncoupled)	Sec 2	Sec 3	Sec 4	Sec 5 (Uncoupled)
ΔW (Etch)	Variable - Unknown				
Pitch	625 mils	126 mils	53 mils	161 mils	625 mils
Spacing (S_{mfg})	X	$S_{des} + 2 * \Delta W$	$S_{des} + 2 * \Delta W$	$S_{des} + 2 * \Delta W$	X
Trace Width (W_{mfg})	$W_{des} - 2 * \Delta W$				
Dk_{mfg}	4.5	4.5	4.5	4.5	45
Copper Thickness	1.2 mils				
Dielectric Height	58.7 mils	58.7 mills	58.7 mils	58.7 mils	58.7 mills
Trace Length	1000 mils	2130 mils	2000 mils	2155 mils	625 mils

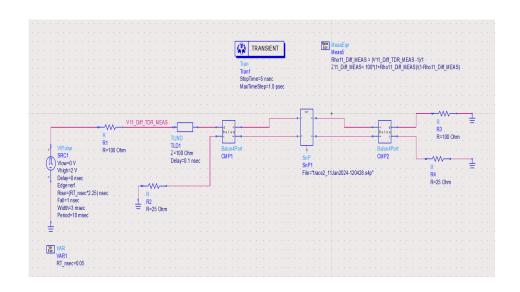
What are the variable parameters and how far can we alter these parameters?

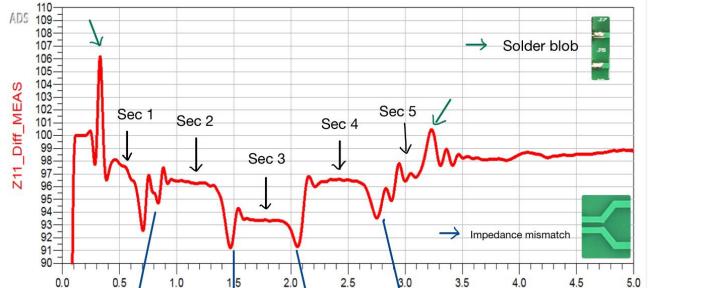
Parameter	Variability factor
Dielectric Constant (Dk)	+/- 0.4
Dielectric height (H)	+/- 2 mils
Etch (del W)	+/- 1 mil



Measured Data

CIRCUIT





Sec 4

Sec 5

TDR PLOT





Sec 1

Sec 2

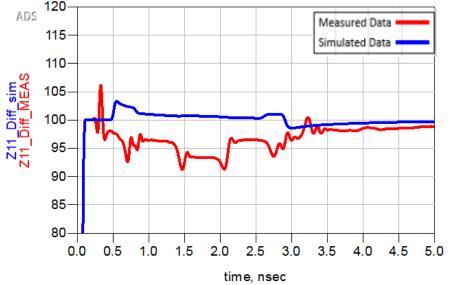
Sec 3

What does this

data represent?

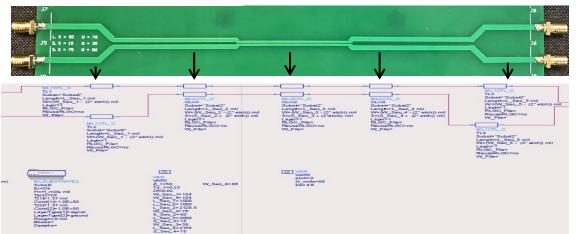
Simulated Data

TDR PLOT



Parameters	Simulated
Dielectric Constant (Dk)	4.5
Dielectric height (H)	58.7 mils
Etch (del W)	0 mil

CIRCUIT



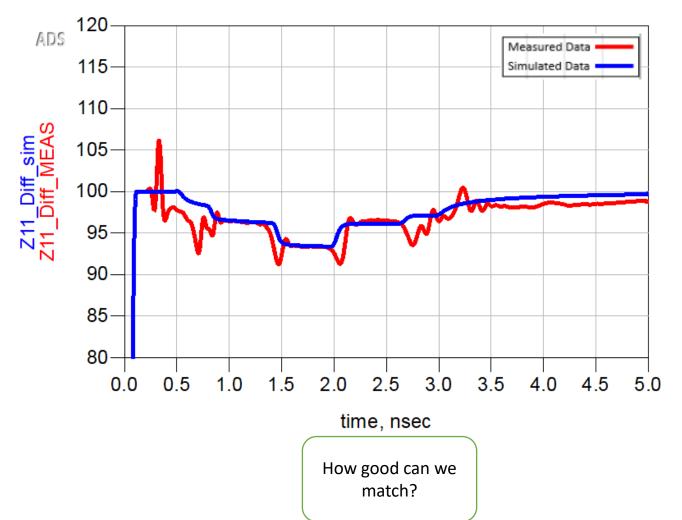
How do we hack?

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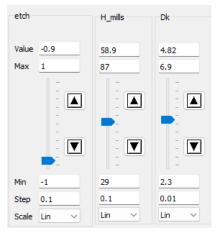




TDR plots Meas vs Sim Data



Parameters	Measured	Simulated
Dielectric Constant (Dk)	4.5	4.82
Dielectric height (H)	58.7 mills	58.9 mills
Etch (del W)	0 mil	-0.9 mils (Over etched)







Key Takeaways

• Understanding the behavior of interconnects and parameters of PCB stack-up.

• Board designs with specific parameters may not always be consistent with what the fabrication vendor produced.

• Hacking the simulation data to fit the measured data allowed a bigger transparency of the parameter values.



Questions?

